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	Filing Date		2004-12-10		
	First Named Inventor	Evert Johannes Bunschoten et al.			
	Art Unit		1616		
	Examiner Name	Mei-Ping Chui			
	Attorney Docket Number		0470-045923		

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1	Office Action mailed on December 19, 2007 in U.S. Patent Application No. 10/S17,509.	
2	Office Action mailed on March 26, 2008 in U.S. Patent Application No. 10/517,509.	
3	Office Action mailed on January 5, 2009 in U.S. Patent Application No. 10/517,509.	
4	Office Action mailed on August 18, 2009 in U.S. Patent Application No. 10/517,509.	
5	Office Action mailed on April 23, 2007 in U.S. Patient Application No. 10/521,040.	
6	Office Action mailed on August 17, 2007 in U.S. Patent Application No. 10/521,040.	
7	Office Action mailed on April 2, 2008 in U.S. Patent Application No. 10/521,040.	
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